

SAMXON BRAND ALUMINUM ELECTROLYTIC CAPACITORS PRODUCT SPECIFICATION 規格書

CUSTOMER: (客戶):志盛翔

DATE: (日期):2017-03-22

CATEGORY (品名)	: ALUMINUM ELECTROLYTIC CAPACITORS
DESCRIPTION (型号)	: SF 100V1000μF(φ18X35)
VERSION (版本)	: 01
Customer P/N	:
SUPPLIER	:

SUPPL	IER	CUSTOMER				
PREPARED (拟定)	CHECKED (审核)	APPROVAL (批准)	SIGNATURE (签名)			
李婷	王国华					

ELECTROLYTIC CAPACITOR SPECIFICATION SF SERIES

		SPECIFICA	ALTERNATION HISTORY RECORDS				
Rev.	Date	SF SERIE Mark	ES Page	Contents	Purpose	Drafter	Approver
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	MAN YUE ELECTRONICS COMPANY LIMITED				ELECTROLYTIC CAPACITOR SPECIFICATION SF SERIES					S	AMX	ON		
Tab	le 1 Product Dimen Safety vent for≥Φ6.3	sions a	nd Ch	aracteristic ↓ ⊕ d±0.0:			\uparrow		20 : α=1.5; L≥			m		
	$L^{+\alpha}_{-1.0}$		5 min	4 min	-	ΦD ⁺ _{-0.5}	F±0.5	* If it is	D<20 : β=0.5; flat rubber, t urface.			from th	ne flat r	ubber
N o.	SAMXON Part No.	WV (Vdc)	Cap. (µF)	Cap. tolerance	Temp. range(℃)	tanδ (120Hz, 20℃)	Leakage Current (µA,2min)	Max Ripple Current at 105℃ 100KHz (mA rms)	Impedance at 20°C 100kHz (Ωmax)	Load lifeti me (Hrs)	Din D×L	nension (mm) F	n фd	Sleev e
1	ESF108M2AL35RR**P	100	1000	-20%~+20%	-40~105	0.08	1000	1790	0.032	6000	18X35	7.5	0.8	PET

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1.		olicatio specificati		plies to polar	Alum	ninum electrol	vtic c	apacitor (f	oil type) us	sed in	n electronic equ	ipmen
				quality meet			<u> </u>	T (- J I - J			1 -
2.	. Par	t Numb	oer S	ystem								
	12	3 4	56	5 7]	89	[101112	131	14	1516	17
	EG	<u>S 1</u>	0 5	<u>5</u> <u>M</u>		<u>1 H</u>	_	D 1 1	<u> </u>	C	SA	Ρ
	SERIES	GAPA	CITAN			VOLTAGE		CASE SIZE	TYP		SAMXON PRODUCT LINE	SLEEV
	Series ESM	Cap(MFD)	Code	Tolerance (%)	Code	Voltage (W.V.) 2	Code	Case Size	Feature (Code	SAMXON Product	
	EKF	0.1	104	±5	J	2.5	0D 0E	3 B	Radial bulk	RR	(The product lines	×
	EKS	0.22	224		- K	4 6.3	0G OJ	3.5 1 4 C 5 D	Ammo Tap	aing	we have H,A,B,C,D	
	EKM EKG	0.33	334	±10	к	8	0K	6.3 E 8 F	2.0mm Pitch	тт	E,M or 0,1,2,3,4,5,9	"·
	EOM EZM			±15	L	10 12.5	1A 1B	10 G 12.5 I			L	
	EZS EGF	0.47	474			16	10	13 J 13.5 V	2.5mm Pitch	TU		
	ESF EGT	1	105	±20	м	20 25	1D 1E	14 4 14.5 A 16 K	3.5mm Pitch	TV	Sleeve Material	Code
	EGK	2.2	225	±30	N	30	11	16 K 16.5 7 18 L	5.0mm Pitch	тс	PET	P
	EGD EGC ERS					32 35	13 1V	18.5 8	Lead Cut &	Form		
	ERF	3.3	335	-40	w	40	1G	20 M 22 N 25 O				
	ERR	4.7	475	-20 0	A	42 50	1M 1H	25 O 30 P 34 W 35 Q	СВ-Туре	СВ		
	ERE	10	106			57	1L	40 R	СЕ-Туре	CE		
	ERH	22	226	-20 +10	С	63 71	11J 1S	42 4 45 6 51 S	HE-Type	HE		
	ERA	<u> </u>		-20 +40	x	75	1 T	63.5 T 76 U	КД-Туре	кр		
	ERC	33	336			80	1K 1R	80 8				
	ENP	47	476	-20 +50	S	90	19	90 X 100 Z Len.(mm) Code	FD-Type	FD		
	ERW	100	107	-10 0	B.	100	2A 20	4.5 45	ЕН-Туре	EH		
	ELP					125	2B	5 05 5.4 54 7 07	PCB Term	nial		
	EQP EDP ETP	220	227	-10 +20	v	150 160	2Z 2C	7.7 77 10.2 T2		sw		
	EHP	330	337	-10 +30	Q	180	2P	11 11 11.5 1A		500		
	EKP	470	477	-10	т	200 215	2D 22	12 12 12.5 1B	Snap-in	sx		
	EFP	2200	228	+50		220	2 N	13 13 13.5 1C		sz		
	EVP			-5 +10	E	230 250	23 2E	20 20 25 25 29.5 2J	Lug	SG		.
	EWR	22000	229	-5 +15	F	275	2T	30 30 31.5 3A		~		
	EWT	33000	339	-5 +20	G	300 310	21 2R	35 35 35.5 3E		05		
	EWF	47000	479			315 330	2F 2U	50 50 80 80		06		
	EWH EWL	100000	10T	0 +20	R.	350	20 2V	100 1L 105 1K 110 1M 120 1N 130 1P 140 10		т5		
	EWB VSS VNS			0 +30	0	360 375	2X 2Q	110 1M 120 1N	Screw	тө		
		150000	15T	0	1	375	2Q 2Y	140 1Q				
		220000	227	+50		400 420	2G 2M	150 1R 155 1E 160 1S		D5		
	VZS	330000	33Т	+15	z	420	2W	165 1F 170 1T		D6		
				+5 +20	D	500 550	2H 25	180 1U 190 1V				
		1000000	10M	+10 +50	Y	600	25 26	200 2L 215 2A				
		1500000	15M	+10	н	630	2J	210 2M 220 2N 240 2Q				
		2200000	22M	+30	п			250 2R				
		3300000	33M					260 2S 270 2T				
3												
~												

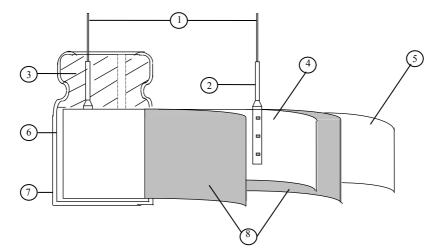
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SAMXON

3. Construction

Single ended type to be produced to fix the terminals to anode and cathode foil, and wind together with paper, and then wound element to be impregnated with electrolyte will be enclosed in an aluminum case. Finally sealed up tightly with end seal rubber, then finished by putting on the vinyl sleeve.



	Component	Material
1	Lead line	Tinned CP wire (Pb Free)
2	Terminal	Aluminum wire
3	Sealing Material	Rubber
4	Al-Foil (+)	Formed aluminum foil
5	Al-Foil (-)	Etched aluminum foil or formed aluminum foil
6	Case	Aluminum case
7	Sleeve	РЕТ
8	Separator	Electrolyte paper

4. Characteristics

Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurements and tests are as follows:

Ambient temperature	:15°C to 35°C
Relative humidity	: 45% to 85%
Air Pressure	: 86kPa to 106kPa

If there is any doubt about the results, measurement shall be made within the following conditions:

Ambient temperature	: 20°C ± 2°C
Relative humidity	: 60% to 70%
Air Pressure	: 86kPa to 106kPa

Operating temperature range

The ambient temperature range at which the capacitor can be operated continuously at rated voltage See table 1 temperature range.

As to the detailed information, please refer to table 2.

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	ITEM				PERFC	RMAN	ЪЕ			
	Rated voltage									
	(WV)	WV (V.DC)	6.3	10	16	25	35	50	63	100
4.1		SV (V.DC)	8	13	20	32	44	63	79	125
	Surge voltage (SV)									
4.2	Nominal capacitance (Tolerance)	Condition> Measuring F Measuring V Measuring T <criteria> Shall be with</criteria>	oltage emperat	: N ture : 20)±2℃	than 0.5V				
4.3	Leakage current	<condition> Connecting t minutes, and <criteria> Refer to Table</criteria></condition>	he capae then, me		-		istor (1	$k \Omega \pm 10$	(Ω) in s	eries for
4.4	tan δ	<condition> See 4.2, Norr <criteria> Refer to Table</criteria></condition>	-	itance, fo	r measu	ring frequ	iency, vo	oltage and	l tempera	ature.
	Terminal	Condition> Tensile Stra Fixed the c seconds. Bending Stra Fixed the ca 90° within 2 seconds.	ength of apacitor rength of pacitor,	r, applied f Termina applied f onds, and	force to lls. force to b then ber Tens	ent the te	rminal (1 0° to its	l∼4 mm f	from the position	rubber) f
4.5	strength	0.5m	nm and I	less		5(0.51)		2.5 (
		Over 0.	5mm to	0.8mm		0 (1.0)		· · · · ·	.51)	
		<criteri< b=""> No notic</criteri<>		nanges sh	all be for	und, no b	reakage	or loosen	ess at the	e termina

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				Testing Tempo		1		Time		
			1		20 ± 2			thermal e	-	
			2	-40(-25)				thermal e		
			3	$20\pm$	2			thermal e	<u>,</u>	
			4	$105 \pm$	2	Time	to reach	thermal e	equilibriu	ım
			5	$20\pm$	2	Time	to reach	thermal e	equilibriu	ım
		<cri< td=""><td>teria></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td></cri<>	teria>							
				within the lin		4.4The le	eakage cu	irrent me	asured s	hall not
	Tomporatura			s of its specifi						
	Temperature characteristi			δ shall be wit	hin the lim	it of Iter	n 4.4The	leakage	current	shall no
4.6	characteristi		than the spe			1 11 /	1.4	1	6.4 6.1	. .
		table	•	C), impedance	e (z) ratio s	hall not e	exceed th	e value (of the fol	lowing
		Work	ing Voltage ((V) 6.3	10	16	25	35	50	63
		Z-2	25°C/Z+20°C	2 4	3	2	2	2	2	2
		Z-4	10°C/Z+20°C	2 8	6	3	3	3	3	3
		Worki	ng Voltage (V) 100	<u>. </u>					
			$25^{\circ}C/Z+20^{\circ}C$		_					
			$\frac{3^{\circ}C/Z+20^{\circ}C}{10^{\circ}C/Z+20^{\circ}C}$		_					
		For capacitance value > $1000 \ \mu$ F, Add 0.5 per another $1000 \ \mu$ F for Z-25/Z+20°C,								
		1010	apacitatice ve	and $\sim 1000 \mu$	T, Auu V.,	per ano				20 C.
		Capac	itance, tan δ	, and impeda	Add 1.0	per anot	her 1000	μF for Z		
		<cor< td=""><td>dition></td><td></td><td>Add 1.0</td><td>per anot e measur</td><td>her 1000 ed at 120</td><td>μ F for Z Hz.</td><td>Z-40°C/Z</td><td>Z+20℃.</td></cor<>	dition>		Add 1.0	per anot e measur	her 1000 ed at 120	μ F for Z Hz.	Z-40°C/Z	Z+20℃.
		<cor Acco</cor 	dition> rding to IEC6	60384-4No.4	Add 1.0 nce shall be	per anot e measur s, The ca	her 1000 ed at 120 pacitor is	HZ.	Z-40°C/Z	2+20°C
		<cor Acco 105°</cor 	Idition> rding to IEC $C \pm 2$ with D	60384-4No.4. C bias voltag	Add 1.0 nce shall b 13 method e plus the r	per anot e measur s, The ca ated ripp	her 1000 ed at 120 pacitor is le curren	μ F for Z Hz. s stored a t for Tab	Z-40°C/Z	Z+20℃ erature he sum
		<cor Acco 105°C DC a</cor 	ndition> rding to IEC($C \pm 2$ with D and ripple pe	60384-4No.4. C bias voltag eak voltage s	Add 1.0 nce shall be 13 method e plus the r hall not ex	s, The ca ated ripp	her 1000 ed at 120 pacitor is le curren e rated w	μ F for Z Hz. s stored a t for Tab yorking v	Z-40°C/Z at a tempole 1. (The voltage)	erature he sum Then th
		<cor Acco 105°C DC a produ</cor 	adition> rding to IEC($C \pm 2$ with D and ripple pe act should be	60384-4No.4 C bias voltag eak voltage s tested after 1	Add 1.0 nce shall be 13 method e plus the r hall not ex 6 hours rec	s, The ca ated ripp	her 1000 ed at 120 pacitor is le curren e rated w	μ F for Z Hz. s stored a t for Tab yorking v	Z-40°C/Z at a tempole 1. (The voltage)	erature he sum Then th
47	Load	Cor Acco 105°C DC a produ result	adition> rding to IEC($C \pm 2$ with D and ripple pe act should be	60384-4No.4. C bias voltag eak voltage s	Add 1.0 nce shall be 13 method e plus the r hall not ex 6 hours rec	s, The ca ated ripp	her 1000 ed at 120 pacitor is le curren e rated w	μ F for Z Hz. s stored a t for Tab yorking v	Z-40°C/Z at a tempole 1. (The voltage)	erature he sum Then th
4.7	life	<pre><cor Acco 105°C DC a produ result <cri< pre=""></cri<></cor </pre>	adition> rding to IEC(2 ± 2 with D and ripple performed be the should be the should meet teria>	60384-4No.4 C bias voltag eak voltage s tested after 1	Add 1.0 nce shall be 13 method e plus the r hall not ex 6 hours rec g table:	s, The ca ated ripp acceed the	her 1000 ed at 120 pacitor is le curren e rated w ime at at	μ F for Z Hz. s stored a t for Tab yorking v	Z-40°C/Z at a tempole 1. (The voltage)	erature he sum Then th
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4.7	life	<pre><cor Acco 105°C DC a produ result <cri< pre=""></cri<></cor </pre>	Idition rding to IEC($C \pm 2$ with D and ripple penet should be should meet teria > characteristic	60384-4No.4 OC bias voltage eak voltage s tested after 1 t the followin c shall meet th arrent	Add 1.0 nce shall be 13 method e plus the r hall not ex 6 hours rec g table: e followin	s, The ca ated ripp acceed the overing t <u>g require</u> 4.3 shall	her 1000 ed at 120 pacitor is le curren e rated w ime at at <u>ments.</u> be satisfi	μ F for 2 Hz. s stored a t for Tab vorking v mospher	Z-40°C/Z at a tempole 1. (The voltage)	erature he sum of Then th
4.7	life	<pre><cor Acco 105°C DC a produ result <cri< pre=""></cri<></cor </pre>	ndition> rding to IECC 2 ± 2 with D and ripple performed be the should be the should meet teria> characteristic Leakage cu Capacitance	60384-4No.4 OC bias voltage eak voltage s tested after 1 t the followin c shall meet th arrent	Add 1.0 nce shall be 13 method e plus the r hall not ex 6 hours rec g table: e followin Value in	s, The ca ated ripp cceed the overing t g require 4.3 shall 25% of	her 1000 ed at 120 pacitor is le curren rated w ime at at ments. be satisfi initial va	μ F for 2 Hz. s stored a t for Tab vorking v mospher ied ilue.	Z-40°C/Z at a tempole 1. (The voltage) ic condit	erature he sum of Then th
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		<criteria></criteria>
		The characteristic shall meet the following requirements.
		Leakage current Value in 4.3 shall be satisfied
	Shelf	Capacitance Change Within $\pm 25\%$ of initial value.
4.8	life	tan δ Not more than 200% of the specified value.
	test	Appearance There shall be no leakage of electrolyte.
		Remark: If the capacitors are stored more than 1 year, the leakage current may
		increase. Please apply voltage through about 1 k Ω resistor, if necessary.
4.9	Surge test	$\label{eq:condition} $$ Applied a surge voltage to the capacitor connected with a (100 ±50)/C_R (k\Omega) resistor. The capacitor shall be submitted to 1000 cycles, each consisting of charge of 30 ±5s, followed discharge of 5 min 30s. The test temperature shall be 15~35°C. C_R :Nominal Capacitance (\mu F) $$ Criteria> $$ Leakage current Not more than the specified value. Capacitance Change Within ±15% of initial value. tan \delta Not more than the specified value. Appearance There shall be no leakage of electrolyte. $$ Attention: This test simulates over voltage at abnormal situation only. It is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such over voltage as often applied. $$ Description of the specified value is not applicable to such $
4.10	Vibration test	<condition></condition> The following conditions shall be applied for 2 hours in each 3 mutually perpendicular directions. Vibration frequency range : $10Hz \sim 55Hz$ Peak to peak amplitude : $1.5mm$ Sweep rate : $10Hz \sim 55Hz \sim 10Hz$ in about 1 minute Mounting method: The capacitor with diameter greater than 12.5mm or longer than 25mm must be fixed in place with a bracket. $4mm$ or less Within 30° $4mm$ or less To be soldered <criteria></criteria> After the test, the following items shall be tested: Inner construction No intermittent contacts, open or short circuiting. No damage of tab terminals or electrodes. Appearance No mechanical damage in terminal. No leakage of electrolyte or swelling of the case. The markings shall be legible.

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4.11	Solderability test	<condition> The capacitor shall be tes Soldering temperature Dipping depth Dipping speed Dipping time <criteria></criteria></condition>	: 245±3°C : 2mm : 25±2.5mr : 3±0.5s		ing
		Coating quality	immersed		
4.12	Resistance to solder heat		or 3^{+1}_{-0} seconds to 1.5~2.0 be left under the normal	to solder bath at 260 ± 5 °C Dmm from the body of cap temperature and normal h	acitor .
4.12	4.12 solder heat test	Leakage current	Not more than	the specified value.	
		Capacitance Change	Within $\pm 10\%$	of initial value.	
		tan δ	Not more than	the specified value.	
		Appearance	There shall be	no leakage of electrolyte.	
4.13	Change of temperature test	placed in an oven, the cor	adition according as below emperature ature (-40 $^{\circ}$ C) (-25 $^{\circ}$ C) rature (+105 $^{\circ}$ C) tal 5 cycle eet the following require Not more than the Not more than the	Time ≤ 3 Minutes 30 ± 2 Minutes 30 ± 2 Minutesrementspecified value.	all be
4.14	Damp heat test	Humidity Test: According to IEC60384-4	f 90~95%R H .at 40 ± 2 ement. Not more than the spe Within $\pm 20\%$ of ini	tial value. of the specified value.	

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The maximum permissible ripple current is the maximum A.C current at 120Hz and can be applied at maximum operating temperature Table-1	4.15	Vent test	Condition> The following test only apply to those products with vent products at diameter ≥Ø6.3 with vent. D.C. test The capacitor is connected with its polarity reversed to a DC power source. Then a current selected from below table is applied. Table 3> Diameter (mm) DC Current (A) 22.4 or less 1 Over 22.4 10 Criteria> The vent shall operate with no dangerous conditions such as flames or dispersion of pieces of the capacitor and/or case.
	4.16	permissible (ripple	at 120Hz and can be applied at maximum operating temperature Table-1 The combined value of D.C voltage and the peak A.C voltage shall not exceed the rated voltage and shall not reverse voltage. Frequency Multipliers: Coefficient (Hz) 50 120 300 1K 100k

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5. It refers to the latest document of "Environment-related Substances standard" (WI-HSPM-QA-072).

	Substances	
	Cadmium and cadmium compounds	
Heavy metals	Lead and lead compounds	
Heavy metals	Mercury and mercury compounds	
	Hexavalent chromium compounds	
	Polychlorinated biphenyls (PCB)	
Chloinated	Polychlorinated naphthalenes (PCN)	
organic	Polychlorinated terphenyls (PCT)	
compounds	Short-chain chlorinated paraffins(SCCP)	
	Other chlorinated organic compounds	
D · (1	Polybrominated biphenyls (PBB)	
Brominated	Polybrominated diphenylethers(PBDE) (including	
organic	decabromodiphenyl ether[DecaBDE])	
compounds	Other brominated organic compounds	
Tributyltin comp	pounds(TBT)	
Triphenyltin con	npounds(TPT)	
Asbestos		
Specific azo con	npounds	
Formaldehyde		
Beryllium oxide		
Beryllium copp	ber	
Specific phthalat	tes (DEHP,DBP,BBP,DINP,DIDP,DNOP,DNHP)	
Hydrofluorocarb	oon (HFC), Perfluorocarbon (PFC)	
Perfluorooctane	sulfonates (PFOS)	
Specific Benzotr	riazole	

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Attachment: Application Guidelines

1.Circuit Design

(2)

- 1.1 Operating Temperature and Frequency
 - Electrolytic capacitor electrical parameters are normally specified at 20°C temperature and 120Hz frequency. These parameters vary with changes in temperature and frequency. Circuit designers should take these changes into consideration.
- (1) Effects of operating temperature on electrical parameters
 a) At higher temperatures, leakage current and capacitance increase while equivalent series resistance (ESR) decreases.
 - b) At lower temperatures, leakage current and capacitance decrease while equivalent series resistance (ESR) increases.
 - Effects of frequency on electrical parameters
 - a) At higher frequencies capacitance and impedance decrease while tanb increases.
 - b) At lower frequencies, ripple current generated heat will rise due to an increase in equivalent series resistance (ESR).
- 1.2 Operating Temperature and Life Expectancy

See the file: Life calculation of aluminum electrolytic capacitor

1.3 Common Application Conditions to Avoid

The following misapplication load conditions will cause rapid deterioration to capacitor electrical parameters. In addition, rapid heating and gas generation within the capacitor can occur causing the pressure relief vent to operate and resultant leakage of electrolyte. Under Leaking electrolyte is combustible and electrically conductive.

(1) Reverse Voltage

DC capacitors have polarity. Verify correct polarity before insertion. For circuits with changing or uncertain polarity, use DC bipolar capacitors. DC bipolar capacitors are not suitable for use in AC circuits.

(2) Charge / Discharge Applications

Standard capacitors are not suitable for use in repeating charge / discharge applications. For charge / discharge applications consult us and advise actual conditions.

(3) Over voltage

Do not apply voltages exceeding the maximum specified rated voltage. Voltages up to the surge voltage rating are acceptable for short periods of time. Ensure that the sum of the DC voltage and the superimposed AC ripple voltage does not exceed the rated voltage.

(4) Ripple Current

Do not apply ripple currents exceeding the maximum specified value. For high ripple current applications, use a capacitor designed for high ripple currents or contact us with your requirements. Ensure that allowable ripple currents superimposed on low DC bias voltages do not cause reverse voltage conditions.

- 1.4 Using Two or More Capacitors in Series or Parallel
- (1) Capacitors Connected in Parallel

The circuit resistance can closely approximate the series resistance of the capacitor causing an imbalance of ripple current loads within the capacitors. Careful design of wiring methods can minimize the possibility of excessive ripple currents applied to a capacitor.

(2) Capacitors Connected in Series

Normal DC leakage current differences among capacitors can cause voltage imbalances. The use of voltage divider shunt resistors with consideration to leakage current can prevent capacitor voltage imbalances.

1.5 Capacitor Mounting Considerations

(1) Double Sided Circuit Boards

Avoid wiring pattern runs, which pass between the mounted capacitor and the circuit board.

When dipping into a solder bath, excess solder may collect under the capacitor by capillary action and short circuit the anode and cathode terminals.

(2)Circuit Board Hole Positioning

The vinyl sleeve of the capacitor can be damaged if solder passes through a lead hole for subsequently processed parts. Special care when locating hole positions in proximity to capacitors is recommended.

(3)Circuit Board Hole Spacing

The circuit board holes spacing should match the capacitor lead wire spacing within the specified tolerances. Incorrect spacing can cause excessive lead wire stress during the insertion process. This may result in premature capacitor failure due to short or open circuit, increased leakage current, or electrolyte leakage.

(4) Clearance for Case Mounted Pressure Relief vents

Capacitors with case mounted pressure relief vents require sufficient clearance to allow for proper vent operation. The minimum clearances are dependent on capacitor diameters as proper vent operation. The minimum clearances are dependent on capacitor diameters as follows.

φ6.3~φ16mm:2mm minimum, φ18~φ35mm:3mm minimum, φ40mm or greater:5mm minimum.

(5) Clearance for Seal Mounted Pressure Relief Vents

A hole in the circuit board directly under the seal vent location is required to allow proper release of pressure.

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(6) Wiring Near the Pressure Relief Vent Avoid locating high voltage or high current wiring or circuit board paths above the pressure relief vent. Flammable, high temperature gas exceeding 100°C may be released which could dissolve the wire insulation and ignite. (7) Circuit Board patterns Under the Capacitor Avoid circuit board runs under the capacitor as electrolyte leakage could cause an electrical short. (8) Screw Terminal Capacitor Mounting Do not orient the capacitor with the screw terminal side of the capacitor facing downwards. Tighten the terminal and mounting bracket screws within the torque range specified in the specification. 1.6 Electrical Isolation of the Capacitor Completely isolate the capacitor as follows. (1) Between the cathode and the case (except for axially leaded B types) and between the anode terminal and other circuit paths (2) Between the extra mounting terminals (on T types) and the anode terminal, cathode terminal, and other circuit paths. 1.7 The Product endurance should take the sample as the standard. 1.8 If conduct the load or shelf life test, must be collect date code within 6 months products of sampling. 1.9 Capacitor Sleeve The vinyl sleeve or laminate coating is intended for marking and identification purposes and is not meant to electrically insulate the capacitor. The sleeve may split or crack if immersed into solvents such as toluene or xylene, and then exposed to high temperatures. CAUTION! Always consider safety when designing equipment and circuits. Plan for worst case failure modes such as short circuits and open circuits which could occur during use. (1) Provide protection circuits and protection devices to allow safe failure modes. (2) Design redundant or secondary circuits where possible to assure continued operation in case of main circuit failure. 2.Capacitor Handling Techniques 2.1 Considerations Before Using (1) Capacitors have a finite life. Do not reuse or recycle capacitors from used equipment. (2) Transient recovery voltage may be generated in the capacitor due to dielectric absorption. If required, this voltage can be discharged with a resistor with a value of about $1k\Omega$. (3) Capacitors stored for long periods of time may exhibit an increase in leakage current. This can be corrected by gradually applying rated voltage in series with a resistor of approximately $1k\Omega$. (4) If capacitors are dropped, they can be damaged mechanically or electrically. Avoid using dropped capacitors. (5) Dented or crushed capacitors should not be used. The seal integrity can be compromised and loss of electrolyte / shortened life can result. 2.2 Capacitor Insertion (1) Verify the correct capacitance and rated voltage of the capacitor. (2) Verify the correct polarity of the capacitor before inserting. (3) Verify the correct hole spacing before insertion (land pattern size on chip type) to avoid stress on the terminals. (4) Ensure that the auto insertion equipment lead clinching operation does not stress the capacitor leads where they enter the seal of the capacitor. For chip type capacitors, excessive mounting pressure can cause high leakage current, short circuit, or disconnection. 2.3 Manual Soldering (1) Observe temperature and time soldering specifications or do not exceed temperatures of 400 °C for 3 seconds or less. (2) If lead wires must be formed to meet terminal board hole spacing, avoid stress on the lead wire where it enters the capacitor seal. (3) If a soldered capacitor must be removed and reinserted, avoid excessive stress to the capacitor leads. (4) Avoid touching the tip of the soldering iron to the capacitor, to prevent melting of the vinyl sleeve. 2.4 Flow Soldering (1) Do not immerse the capacitor body into the solder bath as excessive internal pressure could result.

- (2) Observe proper soldering conditions (temperature, time, etc.) Do not exceed the specified limits.
- (3) Do not allow other parts or components to touch the capacitor during soldering.
- 2.5 Other Soldering Considerations

Rapid temperature rises during the preheat operation and resin bonding operation can cause cracking of the capacitor vinyl sleeve. For heat curing, do not exceed 150°C for a maximum time of 2 minutes.

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- 2.6 Capacitor Handling after Solder
- (1). Avoid movement of the capacitor after soldering to prevent excessive stress on the lead wires where they enter the seal.
- (2). Do not use capacitor as a handle when moving the circuit board assembly.
- (3). Avoid striking the capacitor after assembly to prevent failure due to excessive shock.
- 2.7 Circuit Board Cleaning

Acetone

- Circuit boards can be immersed or ultrasonically cleaned using suitable cleaning solvents for up 5 minutes and up to 60°C maximum temperatures. The boards should be thoroughly rinsed and dried. The use of ozone depleting cleaning agents is not recommended in the interest of protecting the environment.
- (2) Avoid using the following solvent groups unless specifically allowed for in the specification;

Halogenated cleaning solvents: except for solvent resistant capacitor types, halogenated solvents can permeate the seal and cause internal capacitor corrosion and failure. For solvent resistant capacitors, carefully follow the temperature and time requirements of the specification. 1-1-1 trichloroethane should never be used on any aluminum electrolytic capacitor.

- Alkali solvents : could attack and dissolve the aluminum case.
- Petroleum based solvents: deterioration of the rubber seal could result.
- Xylene : deterioration of the rubber seal could result.
 - : removal of the ink markings on the vinyl sleeve could result.
- (3) A thorough drying after cleaning is required to remove residual cleaning solvents which may be trapped between the capacitor and the circuit board. Avoid drying temperatures, which exceed the maximum rated temperature of the capacitor.
- (4) Monitor the contamination levels of the cleaning solvents during use by electrical conductivity, pH, specific gravity, or water content. Chlorine levels can rise with contamination and adversely affect the performance of the capacitor. Please consult us for additional information about acceptable cleaning solvents or cleaning methods.
- 2.8 Mounting Adhesives and Coating Agents
 - When using mounting adhesives or coating agents to control humidity, avoid using materials containing halogenated solvents. Also, avoid the use of chloroprene based polymers. After applying adhesives or coatings, dry thoroughly to prevent residual solvents from being trapped between the capacitor and the circuit board.

3. Precautions for using capacitors

- 3.1 Environmental Conditions
 - Capacitors should not be stored or used in the following environments.
- (1) Temperature exposure above the maximum rated or below the minimum rated temperature of the capacitor.
- (2) Direct contact with water, salt water, or oil.
- (3) High humidity conditions where water could condense on the capacitor.
- (4) Exposure to toxic gases such as hydrogen sulfide, sulfuric acid, nitric acid chlorine, or ammonia.
- (5) Exposure to ozone, radiation, or ultraviolet rays.
- (6) Vibration and shock conditions exceeding specified requirements.

3.2 Electrical Precautions

- (1) Avoid touching the terminals of the capacitor as possible electric shock could result. The exposed aluminum case is not insulated and could also cause electric shock if touched.
- (2) Avoid short circuit the area between the capacitor terminals with conductive materials including liquids such as acids or alkaline solutions.

4. Emergency Procedures

- (1) If the pressure relief vent of the capacitor operates, immediately turn off the equipment and disconnect form the power source. This will minimize additional damage caused by the vaporizing electrolyte.
- (2) Avoid contact with the escaping electrolyte gas which can exceed 100°C temperatures. If electrolyte or gas enters the eye, immediately flush the eyes with large amounts of water.
- If electrolyte or gas is ingested by month, gargle with water.
 - If electrolyte of gas is ingested by month, gargie with water.

5. Long Term Storage

Leakage current of a capacitor increases with long storage times. The aluminum oxide film deteriorates as a function of temperature and time. If used without reconditioning, an abnormally high current will be required to restore the oxide film. This current surge could cause the circuit or the capacitor to fail. After one year, a capacitor should be reconditioned by applying rated voltage in series with a 1000 Ω , current limiting resistor for a time period of 30 minutes. If the expired date of products date code is over eighteen months, the products should be return to confirmation.

5.1 Environmental Conditions

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The capacitor shall be not use in the following condition:

- (1) Temperature exposure above the maximum rated or below the minimum rated temperature of the capacitor.
- (2) Direct contact with water, salt water, or oil.

(3) High humidity conditions where water could condense on the capacitor.

(4) Exposure to toxic gases such as hydrogen sulfide, sulfuric acid, nitric acid, chlorine, or ammonia.

(5) Exposure to ozone, radiation, or ultraviolet rays.

(6) Vibration and shock conditions exceeding specified requirements.

6. Capacitor Disposal

When disposing of capacitors, use one of the following methods.

Incinerate after crushing the capacitor or puncturing the can wall (to prevent explosion due to internal pressure rise). Capacitors should be incinerated at high temperatures to prevent the release of toxic gases such as chlorine from the polyvinyl chloride sleeve, etc.

Dispose of as solid waste.

NOTE: Local laws may have specific disposal requirements, which must be followed.

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